

# High-Temperature Interactions of Silicon-Aluminum Oxynitrides (SiAlONs) with Sodium Fluoride NaF

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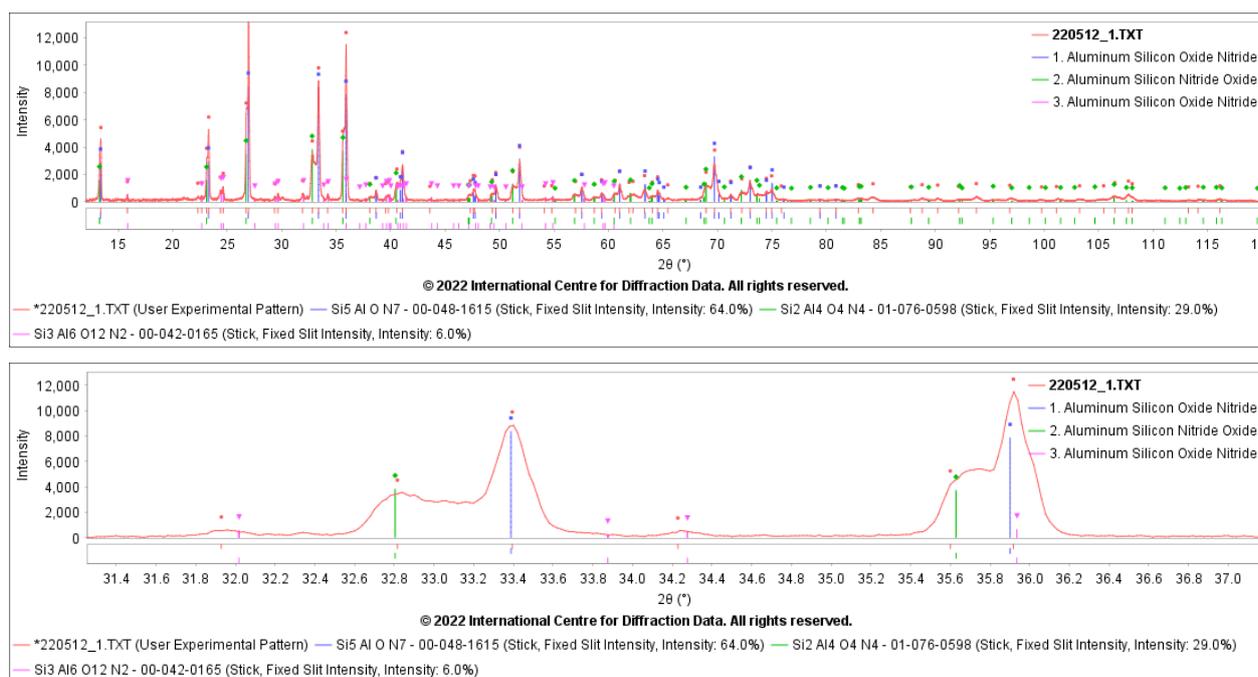


Figure S1. Powder X-Ray Diffraction pattern of the sample SiAlON-1:0.5%NaF.

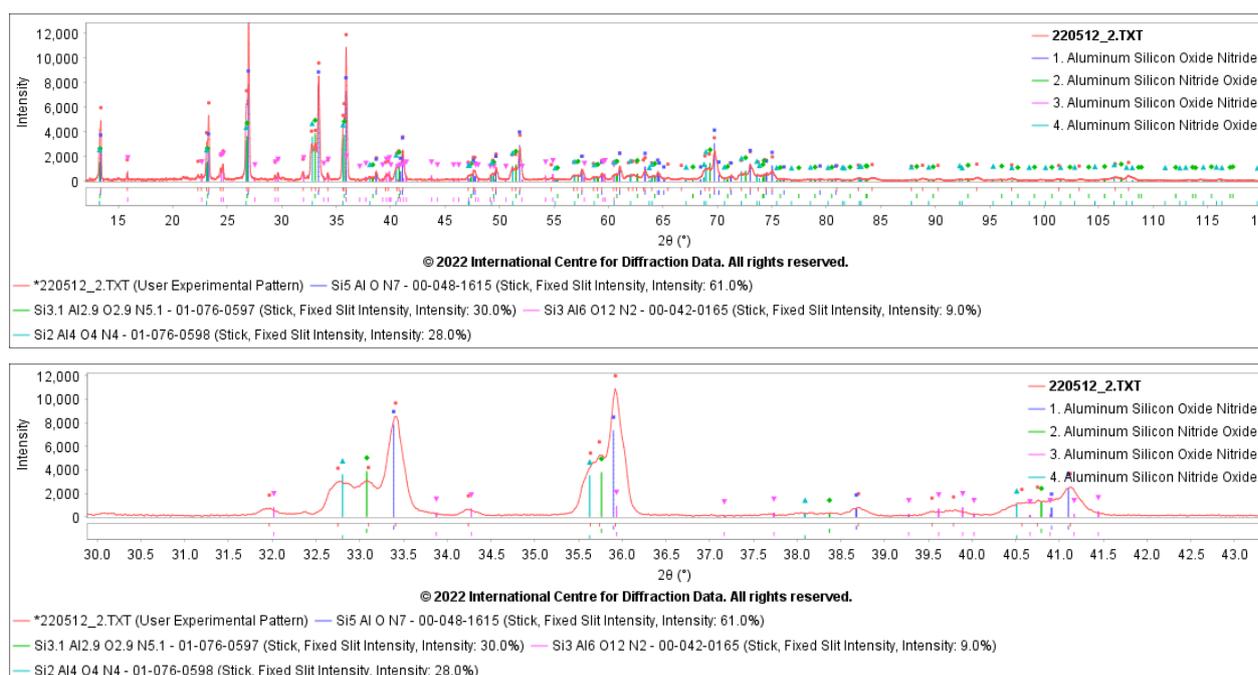
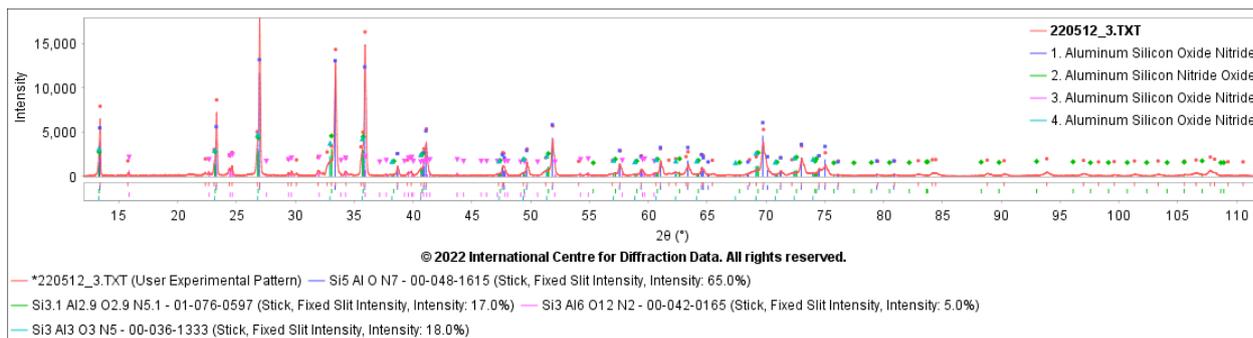
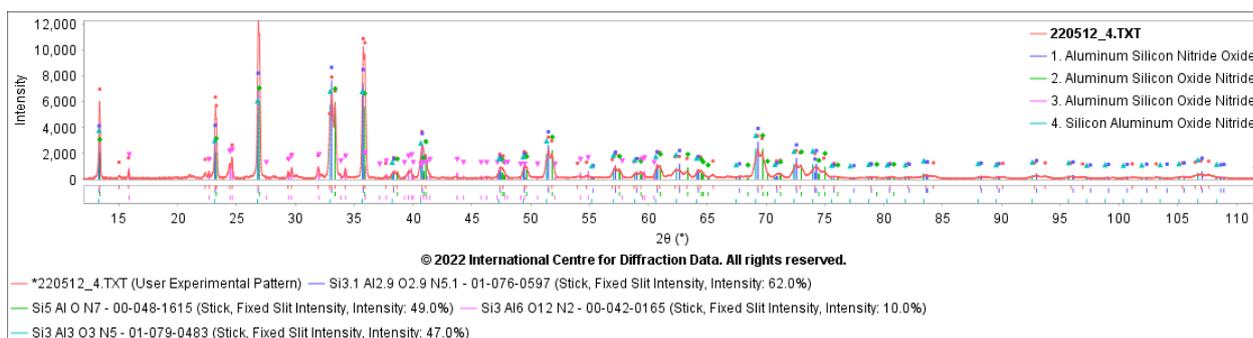


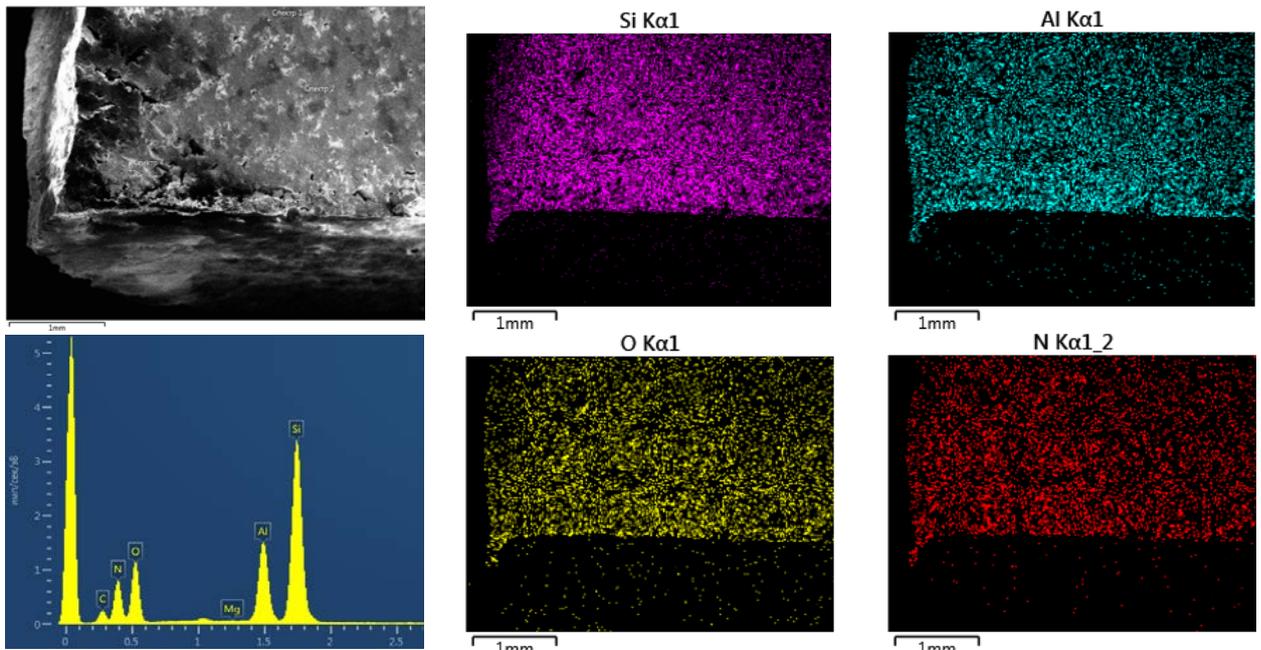
Figure S2. Powder X-Ray Diffraction pattern of the sample SiAlON-1:2.0%NaF.



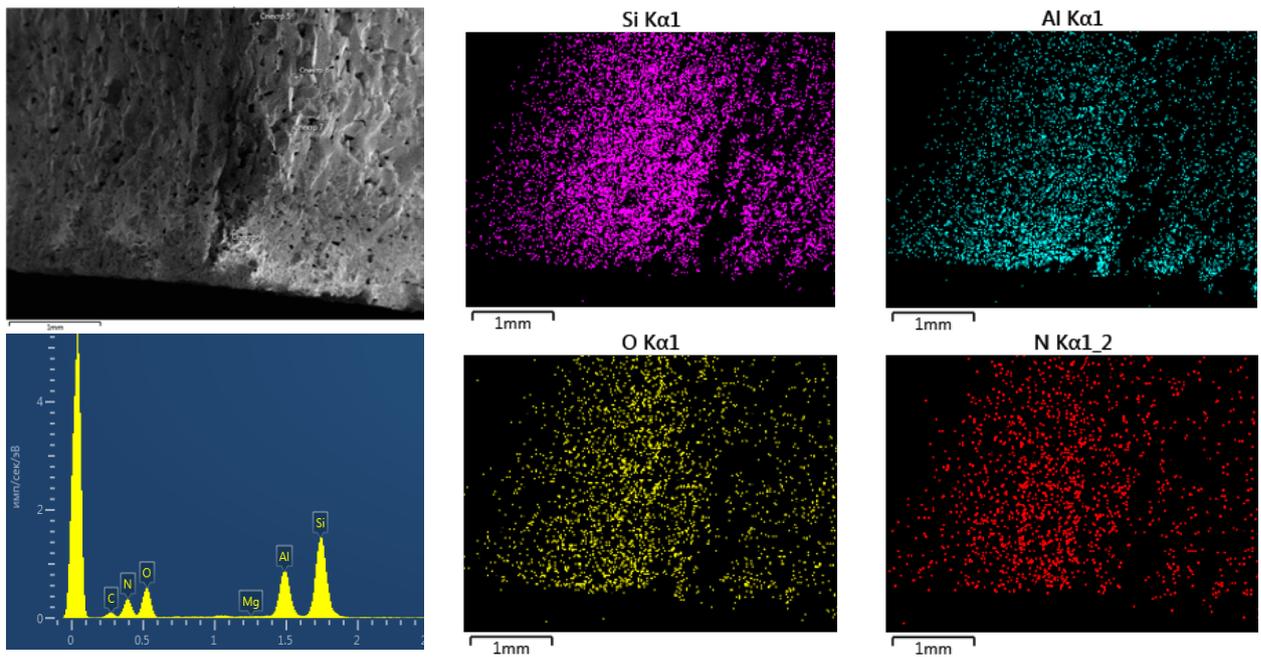
**Figure S3.** Powder X-Ray Diffraction pattern of the sample **SiAlON-2:0.5%NaF**.



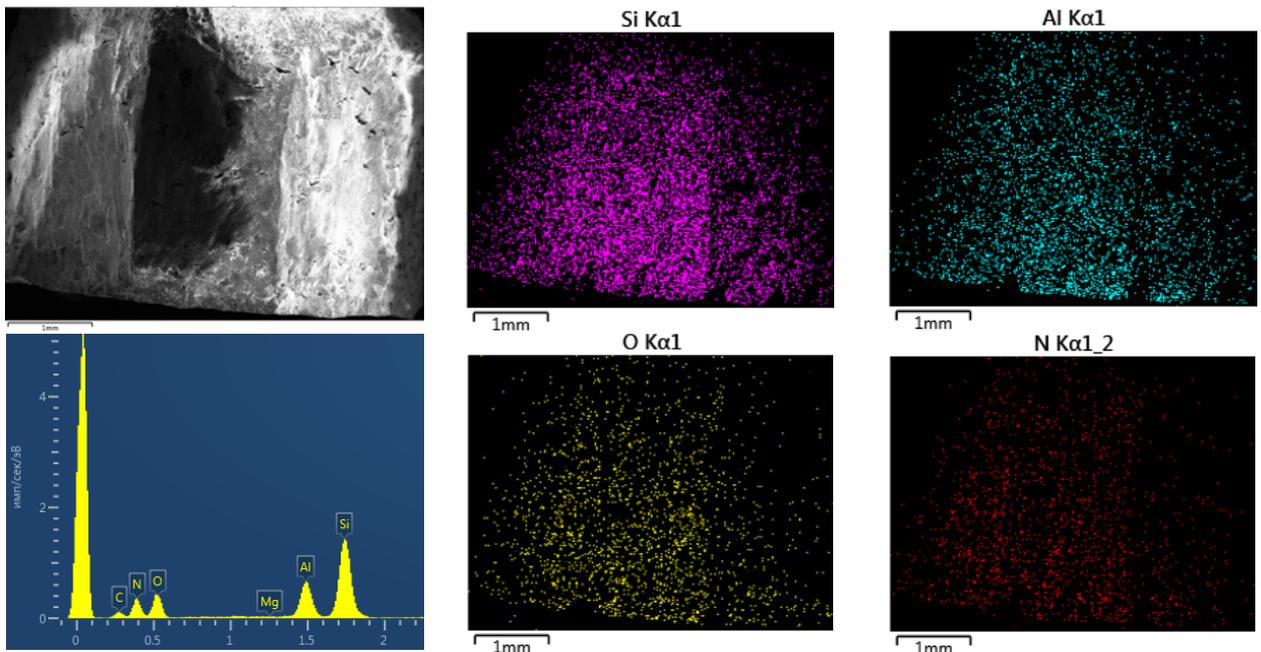
**Figure S4.** Powder X-Ray Diffraction pattern of the sample **SiAlON-2:2.0%NaF**.



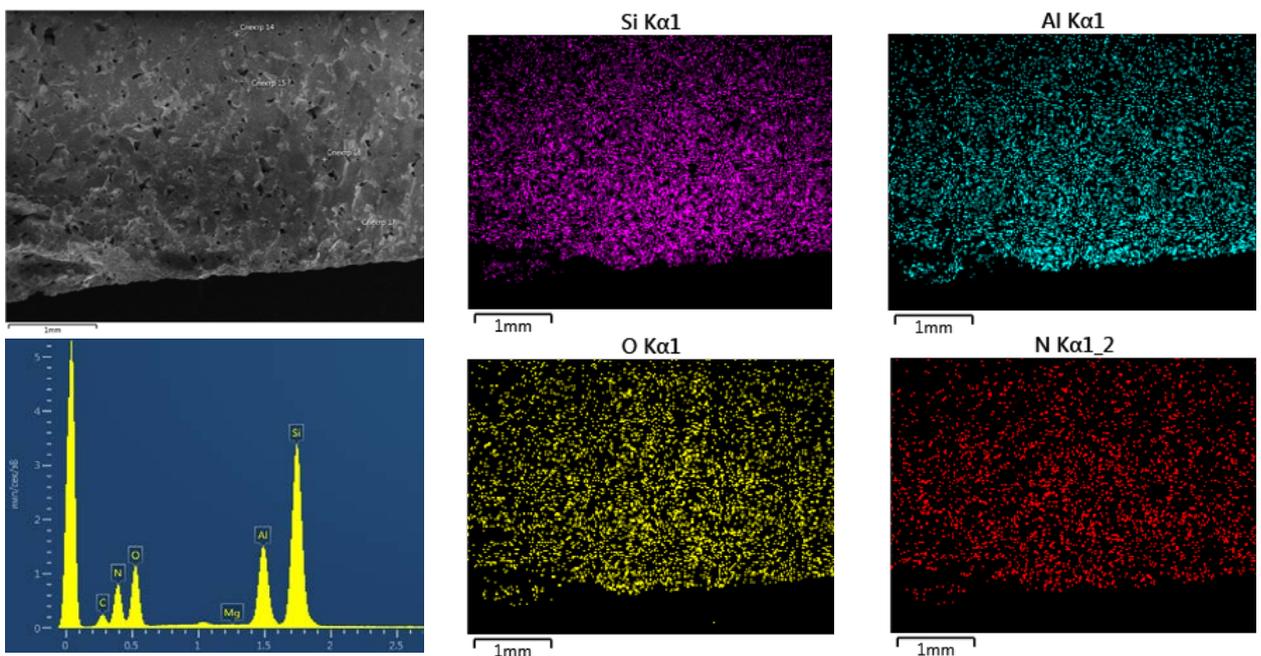
**Figure S5.** SEM images and elemental maps according to EDX spectroscopy data for the sample **SiAlON-1:0.5%NaF**.



**Figure S6.** SEM images and elemental maps according to EDX spectroscopy data for the sample **SiAlON-1:2.0%NaF**.



**Figure S7.** SEM images and elemental maps according to EDX spectroscopy data for the sample **SiAlON-2:0.5%NaF**.



**Figure S8.** SEM images and elemental maps according to EDX spectroscopy data for the sample **SiAlON-2:2.0%NaF**.